

Notice of References Cited

Application/Control No.

10/776,286

Applicant(s)/Patent Under
Reexamination
ONOZAWA ET AL.

Examiner

Leith A. Al-Nazer

Art Unit

2821

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-2002/0175883	11-2002	Onozawa et al.	345/67
	C	US-6,885,225	04-2005	Ohmichi et al.	327/112
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	N	EP 1 139 323 A2	10-2001	Europe	Onozawa et al.	G09G 3/28
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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